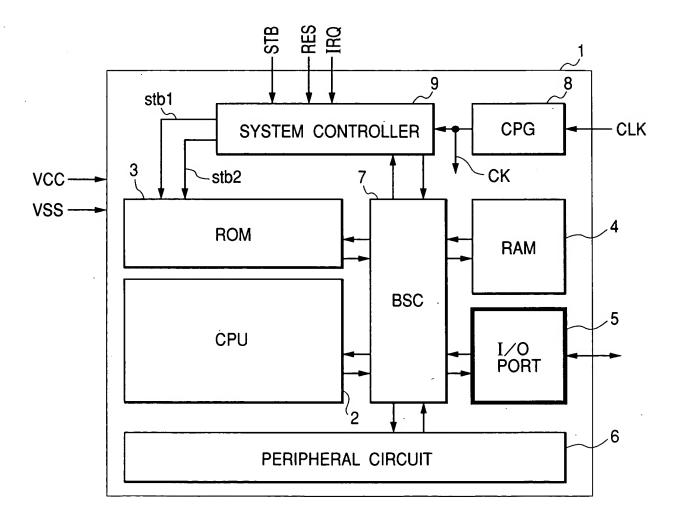
FIG. 1



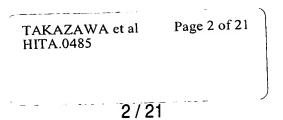


FIG. 2

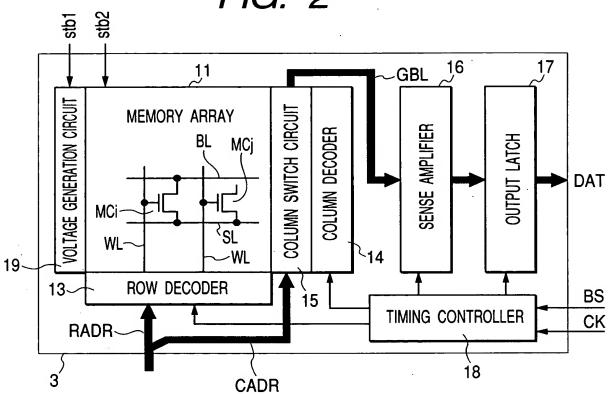
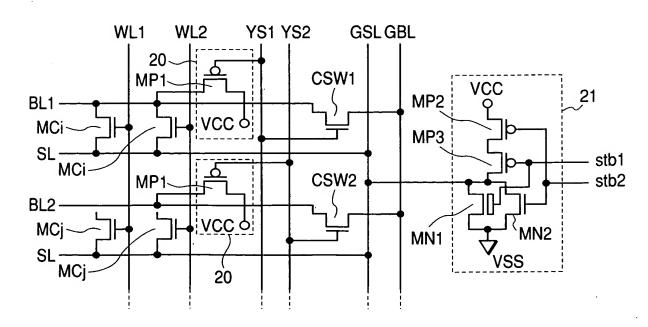
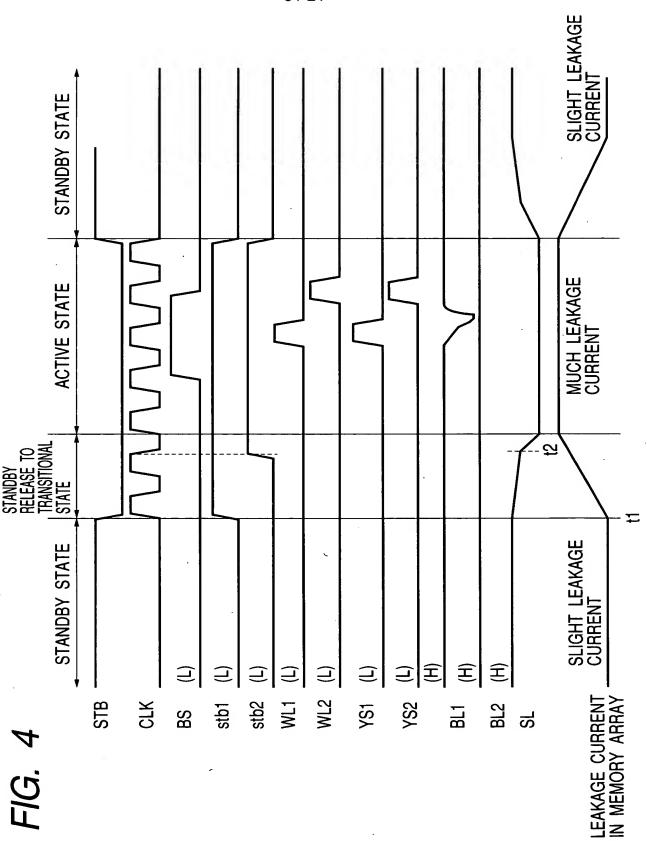


FIG. 3







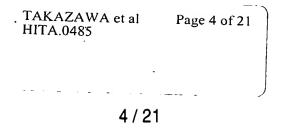


FIG. 5

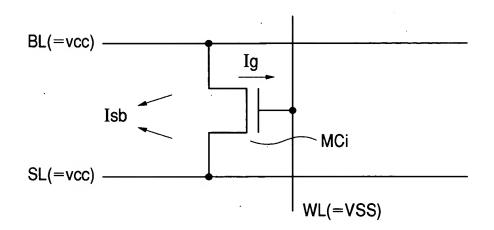


FIG. 6

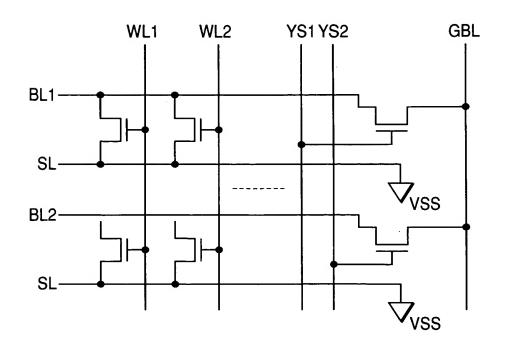
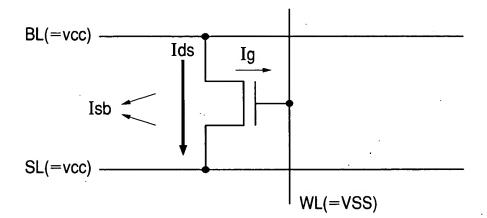


FIG. 7



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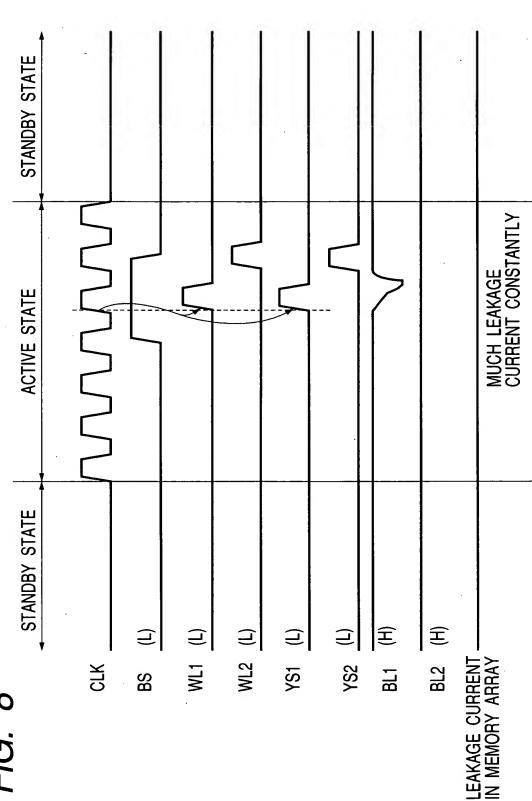


FIG. 8

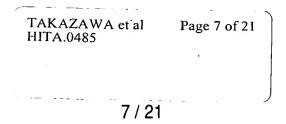
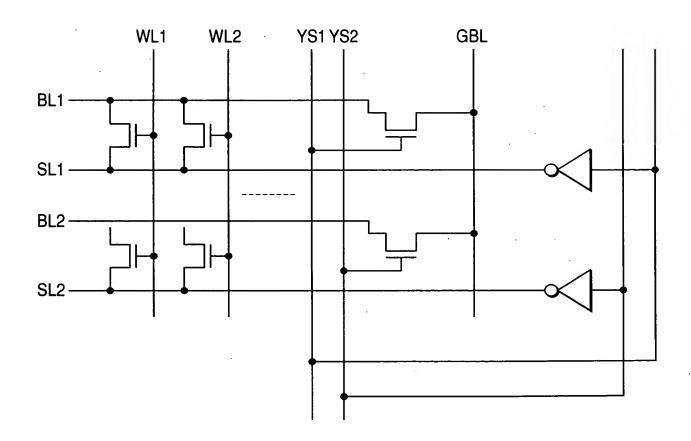
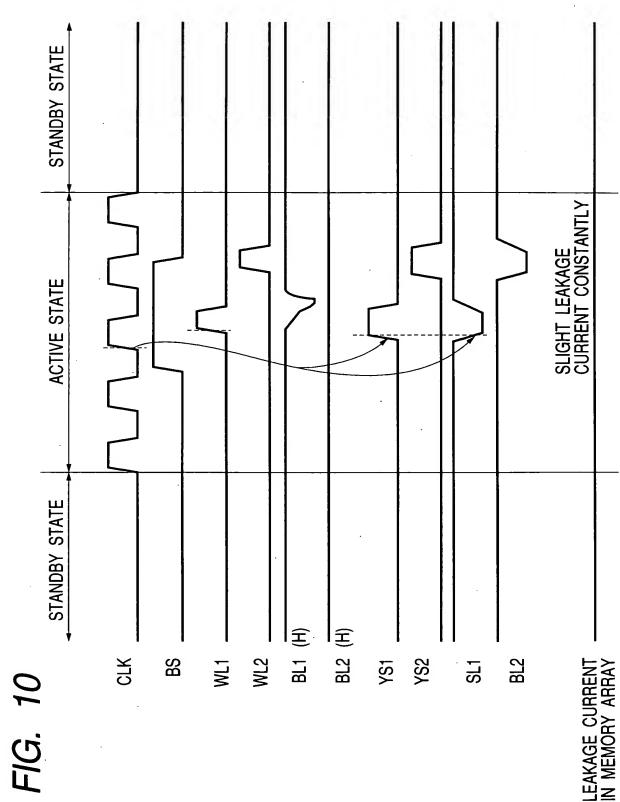
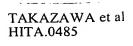


FIG. 9



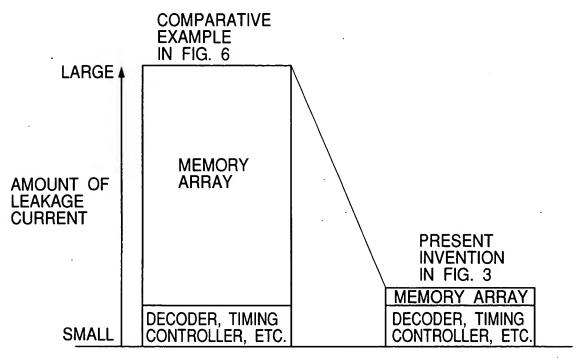




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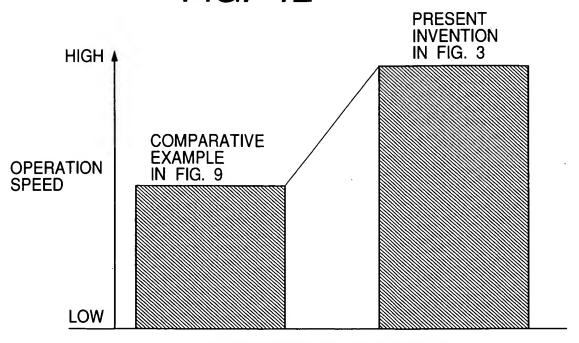
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FIG. 11



EFFECT OF STANDBY LEAKAGE CURRENT REDUCTION (RELATIVE)

FIG. 12



OPERATION SPEED (RELATIVE)

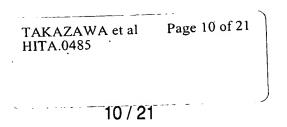


FIG. 13

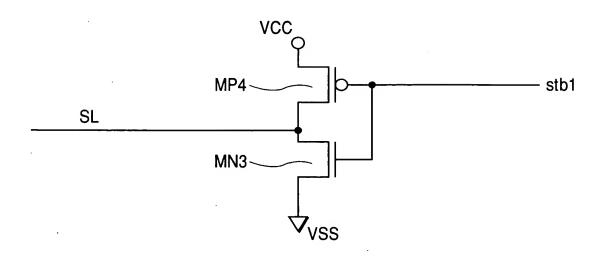
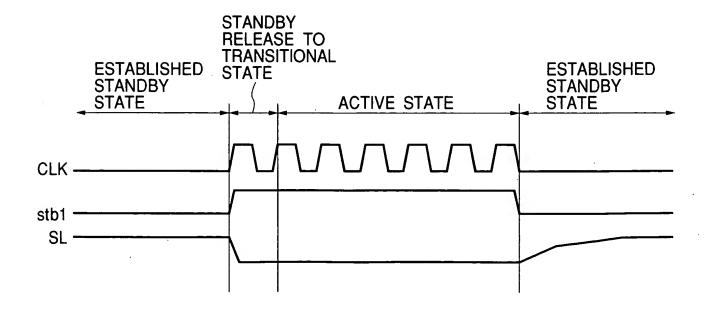
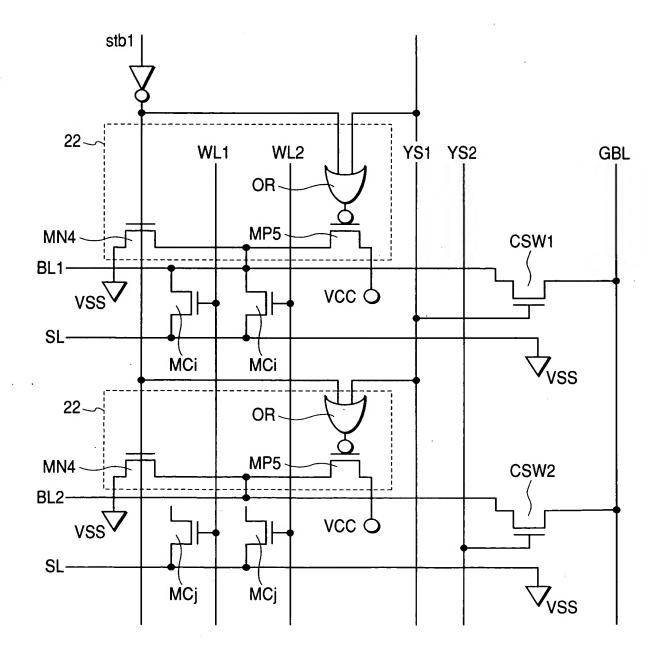


FIG. 14

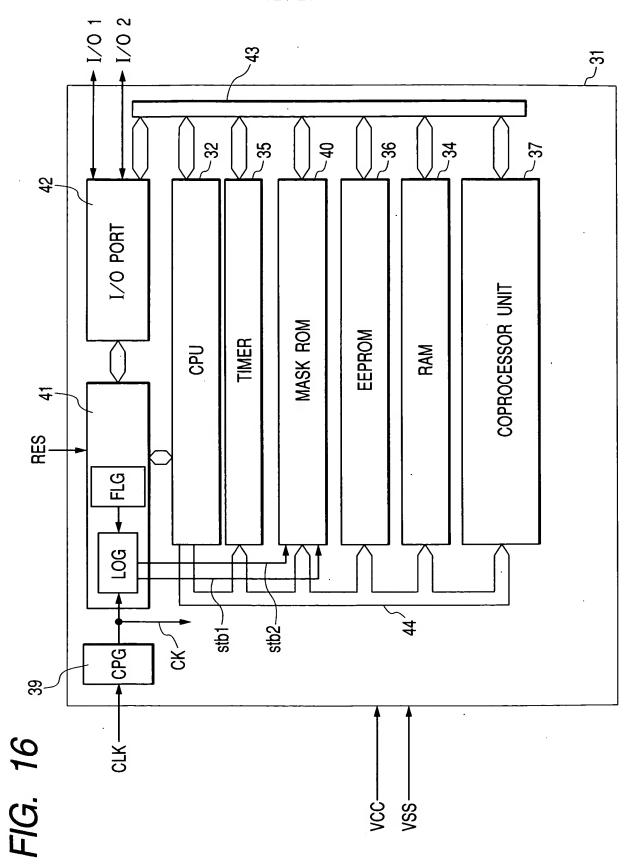


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FIG. 15



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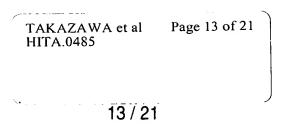


FIG. 17

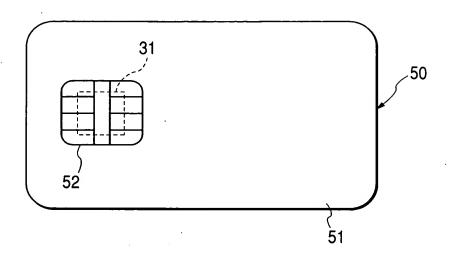
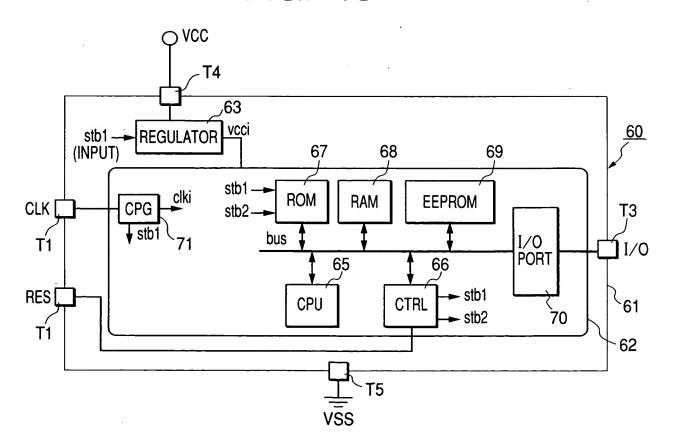


FIG. 18



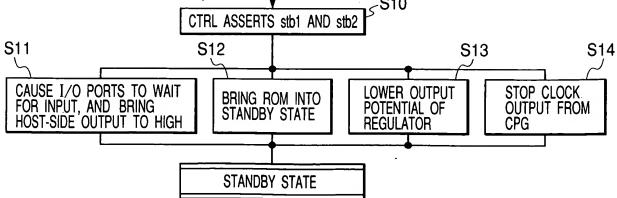
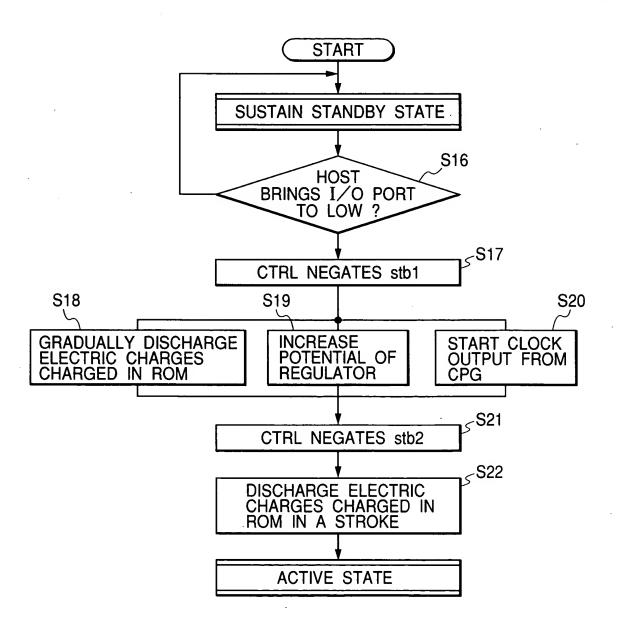
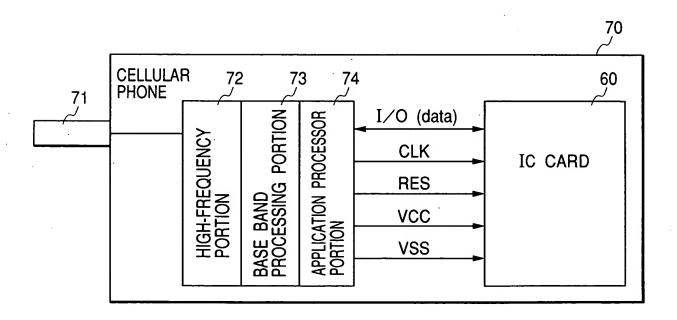


FIG. 20



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FIG. 21



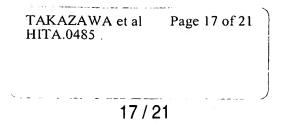
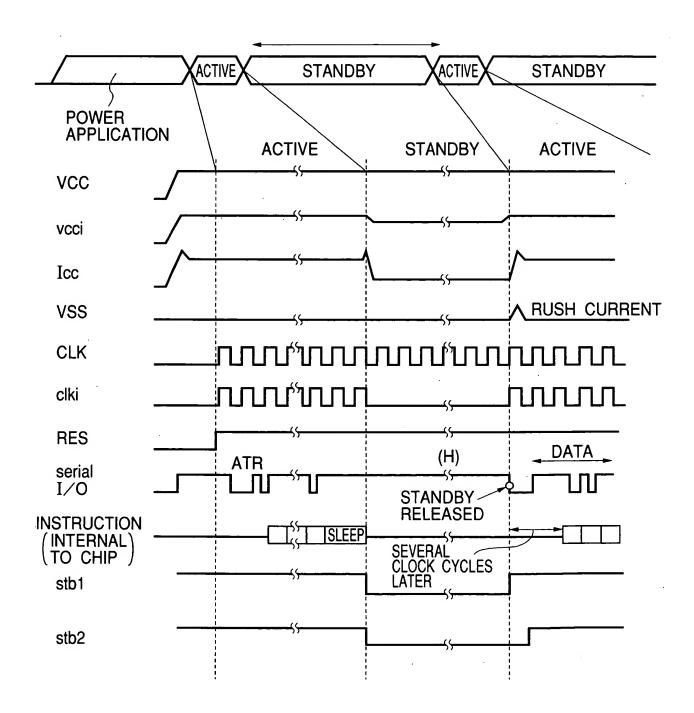


FIG. 22



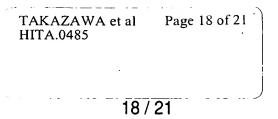


FIG. 23

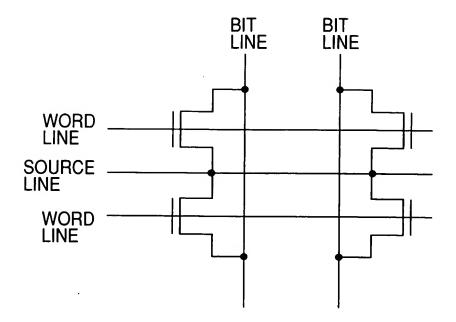
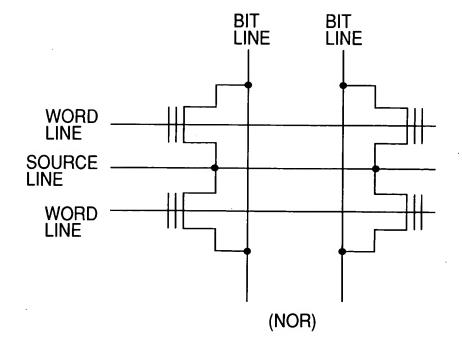


FIG. 24



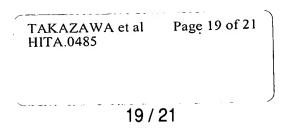
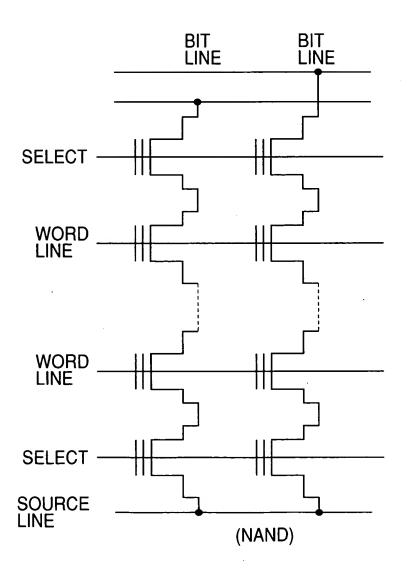


FIG. 25



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FIG. 26

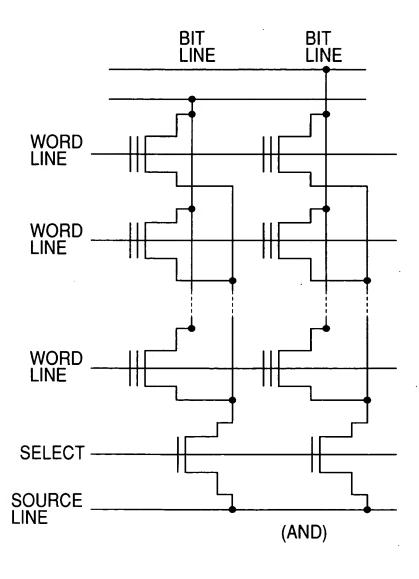


FIG. 27

